at least one optical sensor positioned to view the illuminated OPC, wherein the optical sensor provides a band of captured illumination with gray level picture data of distinguishable pixels which are darker pixels or lighter pixels; and

a controller connectable to the optical sensor for determining a ratio of the number of distinguishable pixels to the total number of pixels in the band, the controller comprising a threshold detector for sensing, based on said ratio, bottom edge wipe (BEW) manufacturing defects in the OPC device.

6. (Amended) A system as in claim 1 wherein the controller is associated with a data storage area, wherein the data storage area may be used to store predetermined threshold values and classification result.

11. (Amended) A method for optically classifying residues on at least one bottom edge area of a OPC, the method comprising the steps of:

illuminating the at least one bottom edge area of the OPC;

capturing reflected illumination from the at least one illuminated bottom edge area of the OPC device, the step of capturing providing a band of captured illumination having gray level picture data of distinguishable pixels which are darker pixels or lighter pixels;

comparing the captured reflected illumination with at least one threshold level, the step of comparing including a step of determining a ratio of the number of distinguishable pixels to the total number of pixels in the band; and

classifying the at least one bottom edge area of the OPC device based upon the comparison of the captured reflected illumination with the at least one threshold level.

16. (Amended) A method for optically classifying residues on at least one bottom edge area of a OPC, the method comprising the steps of:

illuminating the at least one bottom edge area of the OPC;

capturing reflected illumination from the at least one illuminated bottom edge area of the OPC device;

comparing the captured reflected illumination with at least one threshold level; and

classifying the at least one bottom edge area of the OPC device based upon the comparison of the captured reflected illumination with the at least one threshold level;

wherein the step of comparing the captured reflected illumination with at least one threshold level further

comprises the step of comparing the captured reflected illumination with a predetermined pixel count; and

the step of comparing the captured reflected illumination with a predetermined pixel count further comprises the step of comparing the captured reflected illumination with a predetermined gray level pixel count.

20. (Amended) A method for optically discriminating an Organic Photo Conductor (OPC) device, the method comprising the steps of:

illuminating a bottom edge area of the OPC device;

positioning an optical sensor to view the illuminated OPC bottom edge area, the optical sensor providing a band of captured illumination having gray level picture data of distinguishable pixels which are darker pixels or lighter pixels; and

providing a controller connectable to the optical sensor, the controller having a threshold discriminator that determines a ratio of the number of distinguishable pixels to the total number of pixels in the band for classifying the OPC device.

23. (Amended) A method for optically discriminating an Organic Photo Conductor (OPC) device, the method comprising the steps of:

illuminating a bottom edge area of the OPC device;

positioning an optical sensor to view the illuminated OPC bottom edge area; and

providing a controller connectable to the optical sensor, the controller having a threshold discriminator;

wherein the step of providing the controller connectable to the optical sensor further comprises the steps of:

providing a gray level band discriminator;

comparing the ratio of a number of pixels within a predetermined gray level band to the total number of gray level pixels to a predetermined ratio; and

classifying the OPC device as acceptable, non-acceptable, or quasi-acceptable based upon said comparison.

REMARKS

In the Official Action, correction of the drawing was required. The examiner states in Point 1 of the Action that the reference numerals 10 and 12 are used in Fig. 1 to designate a bottom edge. It is proposed to withdraw the previously submitted amendment to Fig. 1, and to enter a second proposed correction of the drawing provided in an accompanying separate paper with correction of the representation of the device under test (DUT), namely, the